

# Search Notes



Application/Control No.

10/056,080

Examiner

Tran Q. Le

Applicant(s)/Patent under  
Reexamination

SHIN-ICHIROU HARASAWA

Art Unit

2633

## SEARCHED

Class	Subclass	Date	Examiner
398	6,11,18	2/11/2005	TQL
"	23,32,33	2/11/2005	TQL
"	37,38,62	2/11/2005	TQL
"	64,97,157	2/11/2005	TQL
"	160,177	2/11/2005	TQL
359	333-349	2/14/2005	TQL
372	70,71	2/16/2005	TQL
	82,83,88	2/16/2005	TQL
ABOVE UPDATED	SEARCH	8/4/05	DS

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Jason C.	2/11/2005	TQL
Inventor check	2/11/2005	TQL
EAST (us-P&Pub; usPAT; EPO; JPO) See Search Results Printout	8/4/05	DS